What's New in VEO Version 3.2.5 R1

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24/06/2012

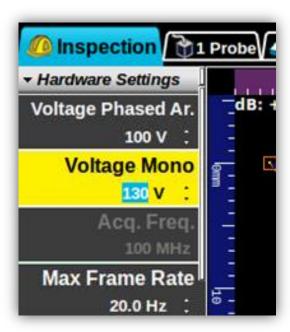
Unique to 16:128 features

- 130 Volts Pulser
- 5 & 6 Concurrent Scans Capability



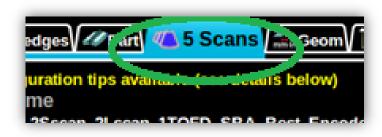
130 Volts Pulser

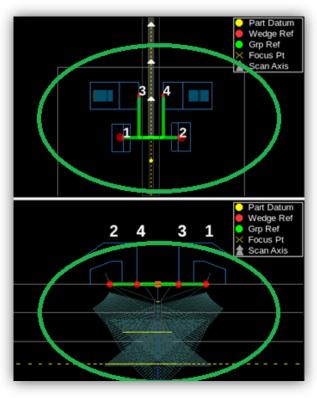
- Improved penetration on:
 - thick part
 - high attenuation material



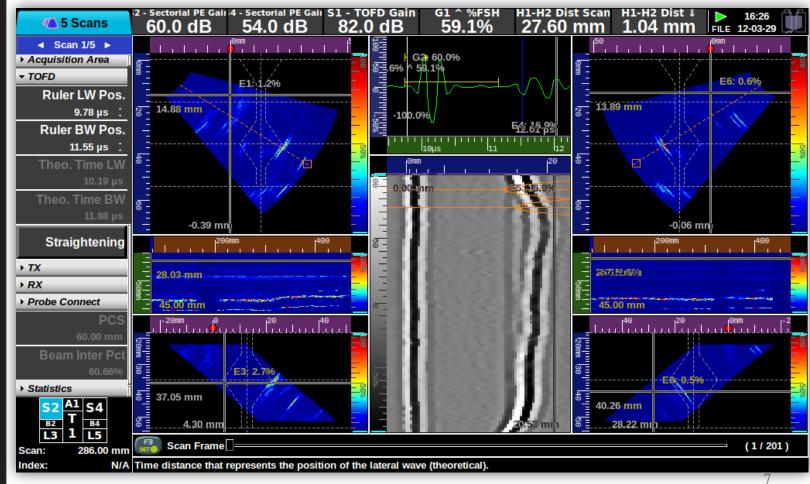
5 & 6 Scans Setup

- Extend Multi-Scan and Multi-Probe capability
- Improve recording process with a single pass including multiple scans





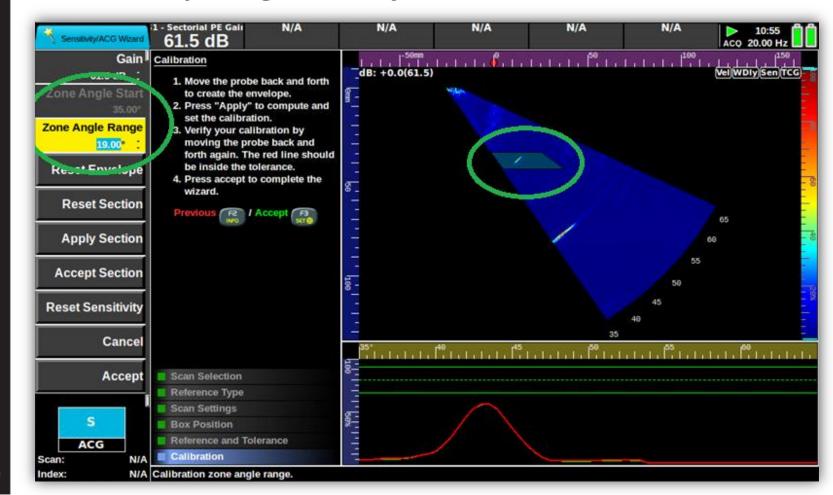
5 & 6 Scans layouts (4)



New Features Available on 16:64 and 16:128

Sensitivity/ACG by section

 Isolate reflector from reflection created by normal part geometry

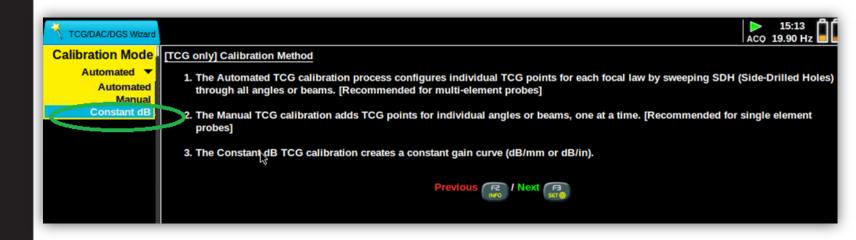


TCG enhancement

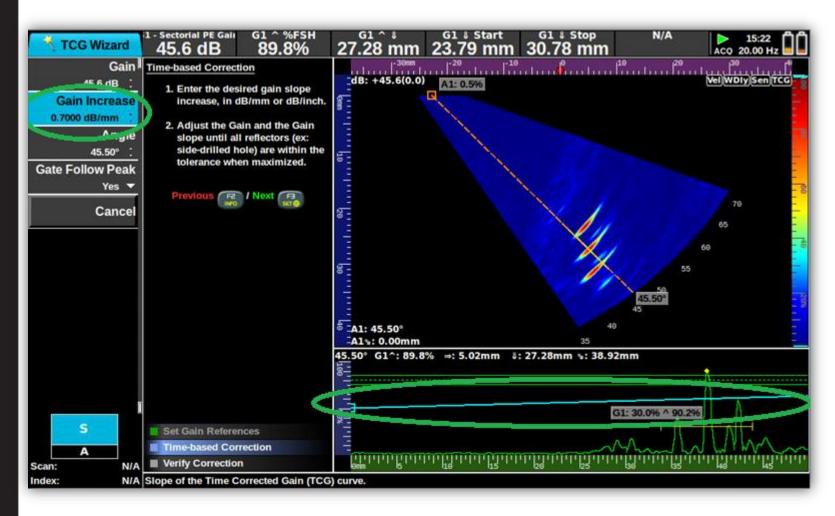
- Create a TCG curve with a "constant dB" generation mode (Theoretical dB/mm or dB/inch)
- Edit the TCG curve generated by the "constant dB" function
- Allow <u>TCG on RF signal</u>
- •Convert the <u>TCG to DAC to TCG</u>

Create a TCG curve with "Constant dB" generation mode

- When material attenuation is known, this mode can accelerate TCG calibration
- Create a good starting point for TCG curve customization

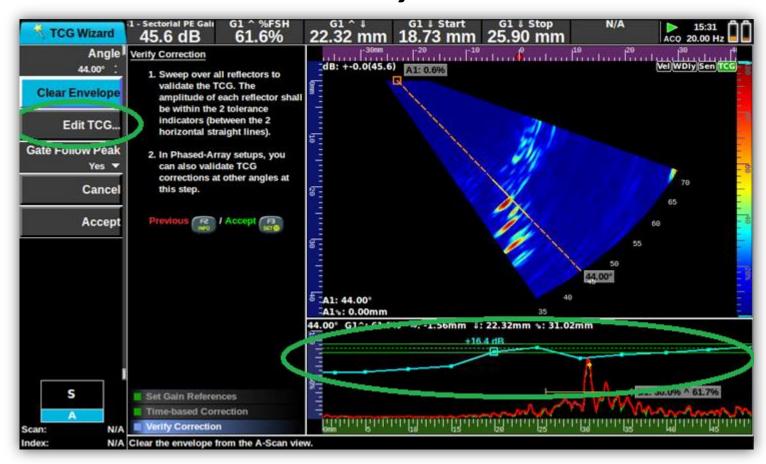


Create a TCG curve with "Constant dB" generation mode



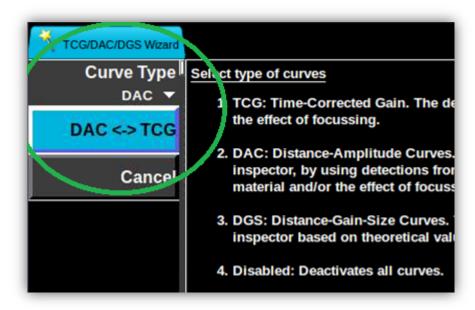
Edit the TCG curve generated by the "constant dB" function

Customize the curve to your needs

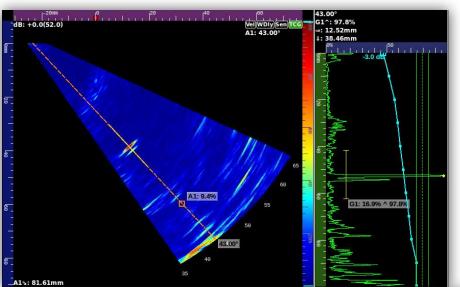


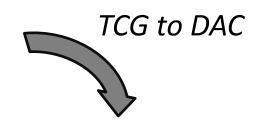
Convert the TCG to DAC to TCG

- Switch between DAC and TCG mode
- Detect with the TCG mode, measure with the DAC mode

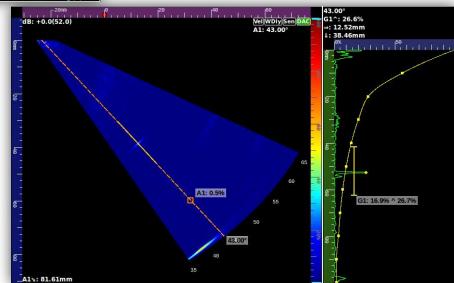


Convert the TCG to DAC to TCG



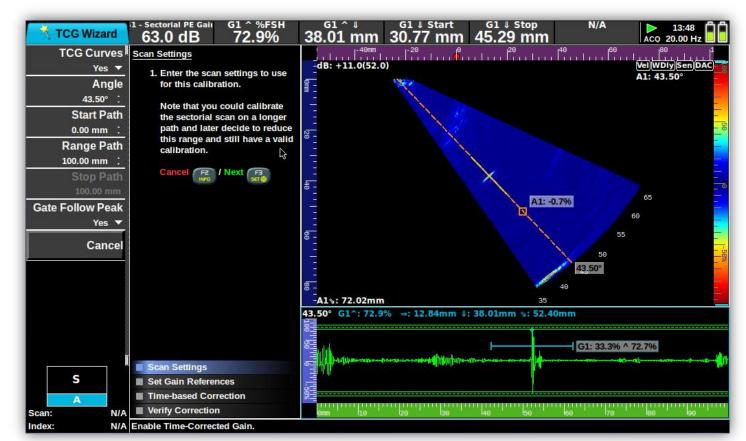






TCG on RF signal

- Ease "Sonatest Wheel Probe" calibration
- TCG on composite material can be realized with a RF signal

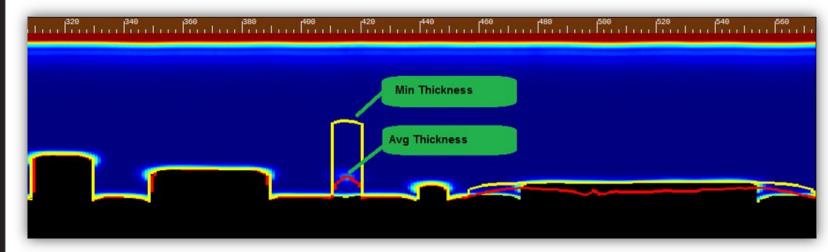


New B-LOG type view (in analysis on device)

• Complete new feature

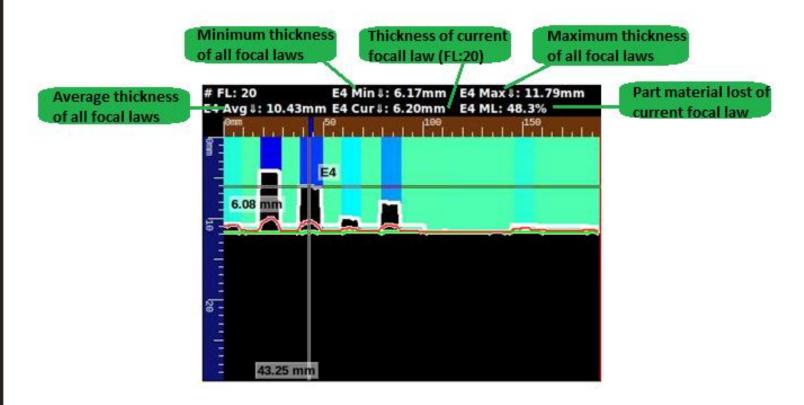
B-Log view (in Phased Array analysis mode)

- Extract Data from gates to render a B-Scan from selected a beam
- Render minimum, average, and maximum part thickness extracted from multiple beams of an L-Scan
- Amplitude and Depth view using flank or peak as reference.



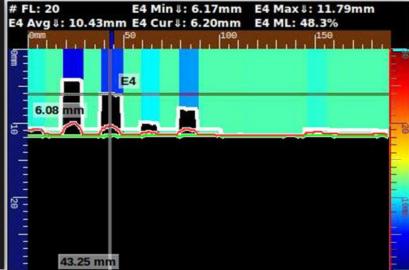
Limitation: Only support probes at 0 degree. Average, Minimum and Maximum thickness is extracted from a single scan axis C-SCAN (not a merged C-Scan) $$_{21}$$

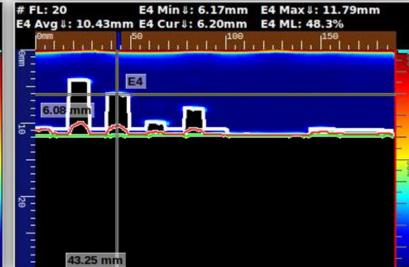
B-Log Measurements



B-Log options

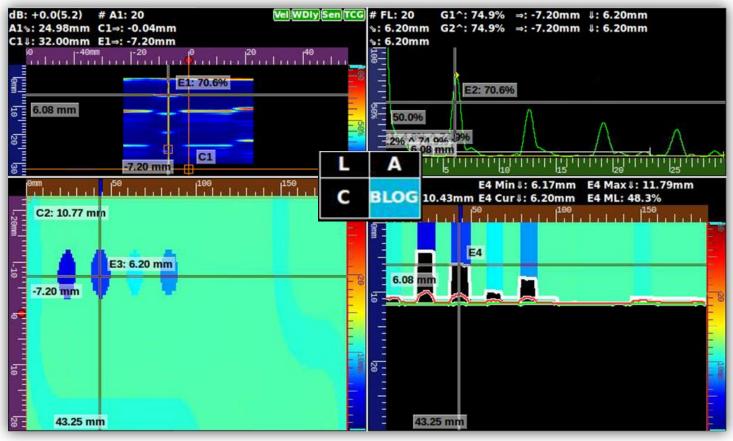
- B-Log view support zoom
- Options are available in view tab (when B-Log view is selected), data can be filtered using reference gate (optional) and data gate. (IFT, G1/, G1^,...)
- Depth (Time of Flight) or Amplitude mode





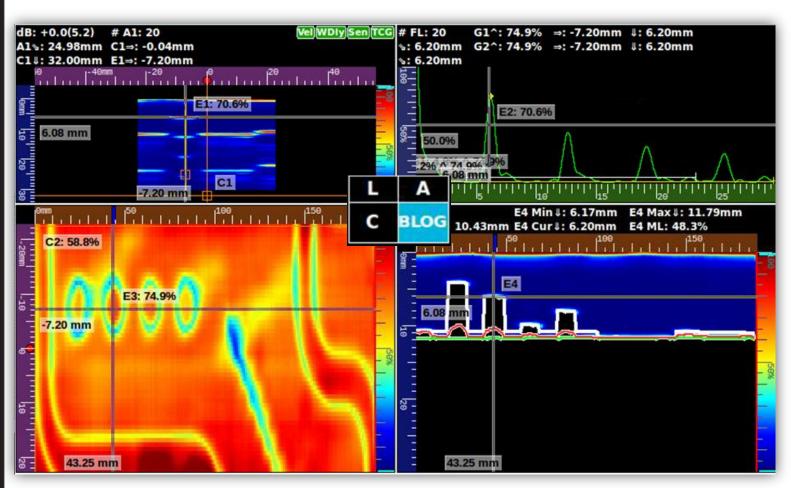
Depth C-Scan and B-Log

B-Log complement to C-Scan view

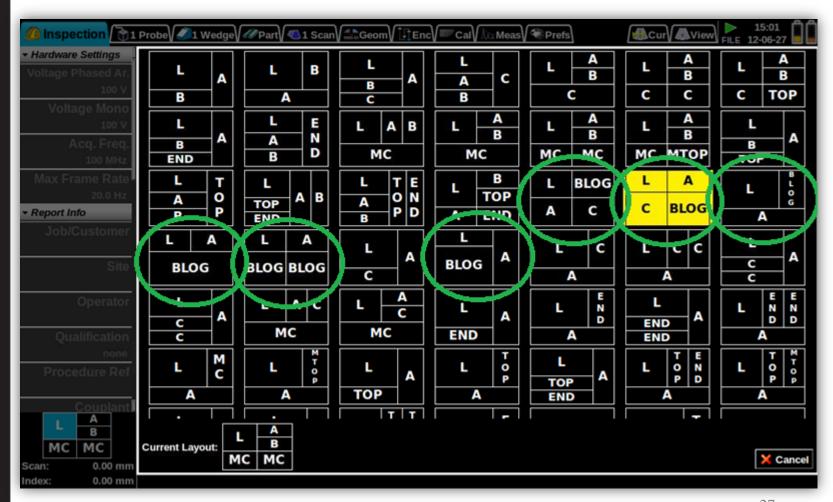


Limitation: Only support probes at 0 degree

Amplitude C-Scan and B-Log



Several B-Log layout

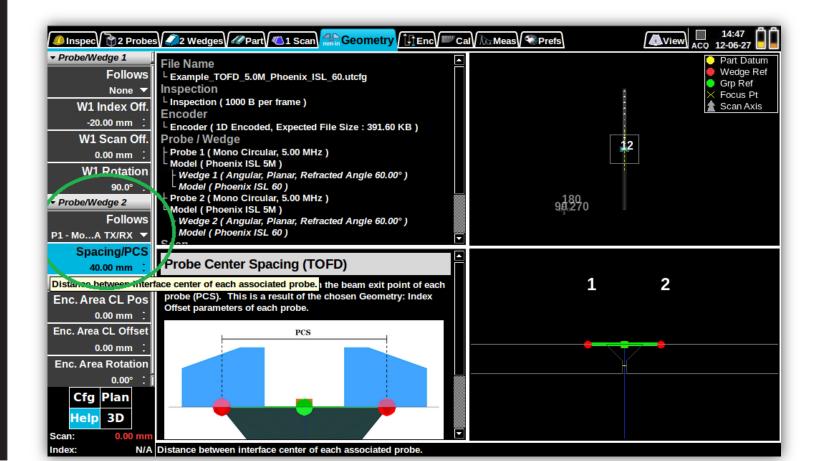


TOFD enhancement

- Edit the PCS directly with the new "Geometry menu" for paired probe
- Calibrate your TOFD scan with 1 parameter "Ruler LW Position"
- Added feature: Lateral Wave Removal

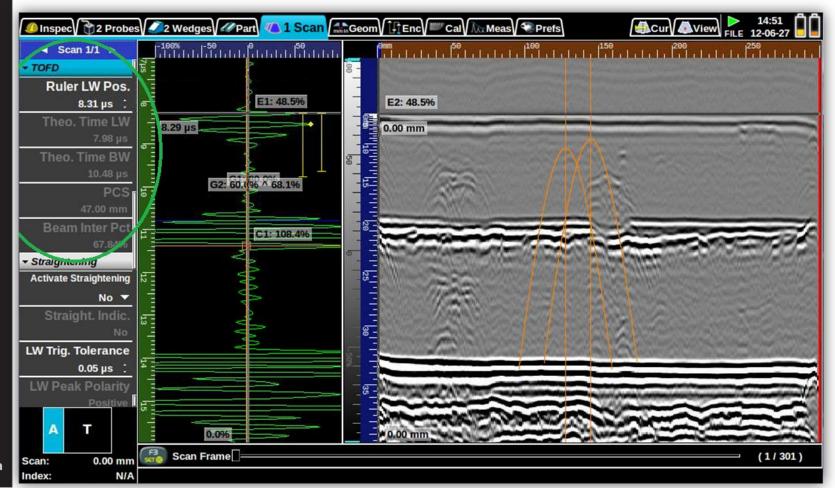
Edit the PCS directly with the new "Geometry menu" for paired probe

 Rapidly configure your probe with the "follows" option, allowing to locate with one parameter: <u>PCS</u>



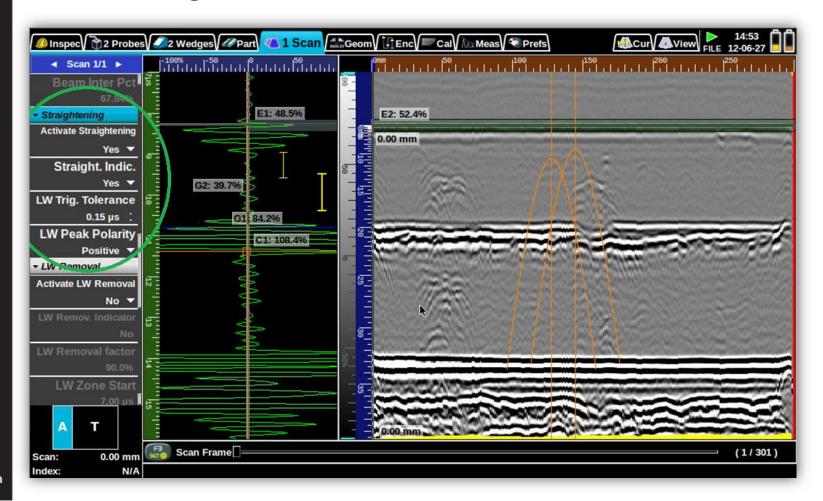
Calibrate your LW position with "Ruler LW Position" only

Lock the parameter "Ruler BW Position" to avoid misleading calibration



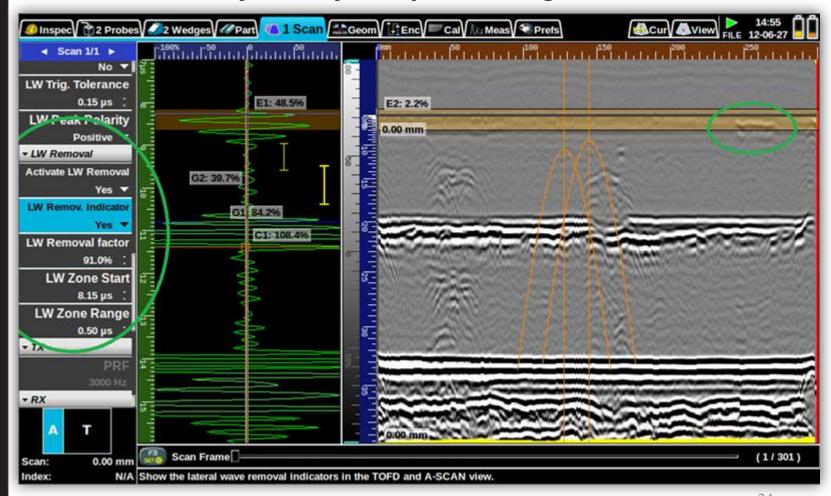
Enhanced Straightening

Lock the parameter "Ruler BW Position" to avoid misleading calibration



Added feature: Lateral Wave Removal tool

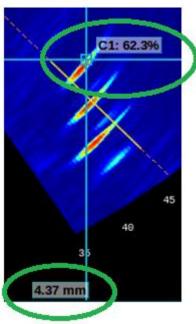
Find near surface defect by removing the "Lateral Wave"

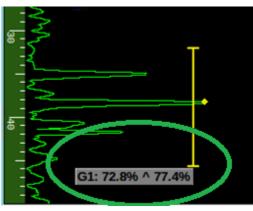


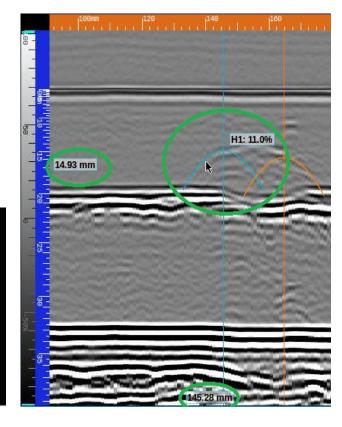
And MORE...

Measurement overlay enhancement for readability

- Easier to read measurement,
- Not hiding scan data

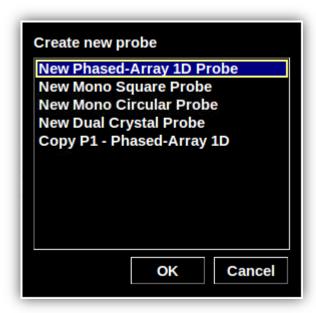


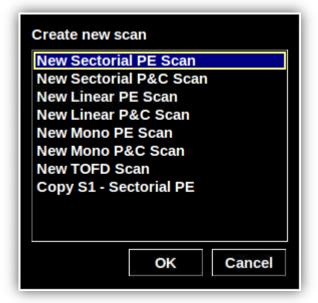




Copy existing probe/scan

- Copy Probe, Wedge and Scan
- Easier to add a new scan to your setup





Ruler considering skip cursor (weld overlay)

- Ruler are adapted to weld overlay
- Proper gate information can be displayed in measurement view

